ABSTRACT

[00025]   A method for testing a device-under-test (DUT) includes examining a test data file that includes test data for testing the structure, functionality and/or performance of the DUT. The method also includes separating a first plurality of data units from a second plurality of data units contained in the test data file. The first plurality of data units correspond to a first plurality of DUT pins, and the second plurality of data units correspond to a second plurality of DUT pins.